

**AMENDMENTS TO THE SPECIFICATION**

Please replace the paragraph beginning at page 23, line 22, with the following rewritten paragraph.

--In addition, it is possible to control the temperature coefficients and the values of the DC resistance **Zdc** and the AC impedance **Zac** in addition to the constant-current circuit **3**. In place of the coil portion **A** explained in FIG. 14, a coil portion **A** is used, which comprises a circuit element **5** composed of a DC resistance **Zdc'** and an AC impedance **Zac'** and connected in series to the coil **2**. At this time, the DC resistance **Zdc'** and the AC impedance **Zac'** of the circuit element **5** have no relation with the rotation angle  $\Theta$  of the core **1**. Therefore, by appropriately selecting the temperature coefficients and the values of the DC resistance **Zdc'** and the AC impedance **Zac'**, it is possible to control the temperature coefficient and the peak value of the voltage detected at both ends of the coil portion **A**--

Please replace the paragraph beginning at page 33, line 1, with the following rewritten paragraph.

--On the other hand, FIG. 24 shows a temperature coefficient of the signal **V2** under the condition of changing the level shift value **Vsh** from 0 mV to 200 mV by use of the device configuration of FIG. 20. The direct current **Idc** is zero, and the temperature coefficient **h** of the level shift value **Vsh** is 3000 ppm/°C. In this case, it is possible to control the displacement dependency of the temperature coefficient of the signal **V2** by changing the level-shift shift value **Vsh**. When the value **Vsh** is in the vicinity of 100 mV, the displacement dependency of the temperature coefficient of the signal **V2** can be minimized. As a result, the same effects as the case of FIG. 19 can be obtained.--